SDLS008

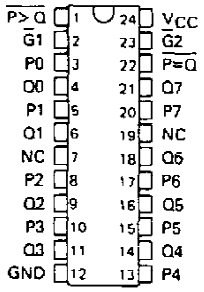
SN54LS682, SN54LS684, SN54LS685, SN54LS687, SN54LS688, SN74LS682, SN74LS684 THRU SN74LS688 8-BIT MAGNITUDE/IDENTITY COMPARATORS

D2617, JANUARY 1981 – REVISED MARCH 1988

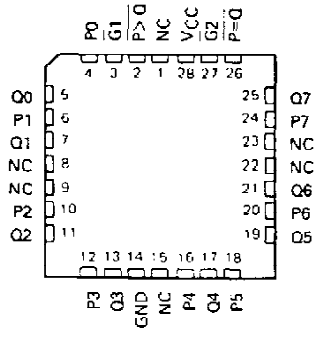
- Compares Two 8-Bit Words
- Choice of Totem-Pole or Open-Collector Outputs
- Hysteresis at P and Q Inputs
- 'LS682 has 20-kΩ Pullup Resistors on the Q Inputs
- SN74LS686 and 'LS687 . . . JT and NT 24-Pin, 300-Mil Packages

TYPE	$\overline{P = Q}$	$\overline{P > Q}$	OUTPUT ENABLE	OUTPUT CONFIGURATION	20-kΩ PULLUP
'LS682	yes	yes	no	totem-pole	yes
'LS684	yes	yes	no	totem-pole	no
'LS685	yes	yes	no	open-collector	no
SN74LS686	yes	yes	yes	totem-pole	no
'LS687	yes	yes	yes	open-collector	no
'LS688	yes	no	yes	totem-pole	no

SN54LS687 . . . JT PACKAGE
SN74LS686, SN74LS687 . . . DW OR NT PACKAGE
(TOP VIEW)

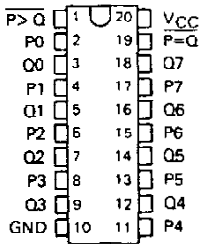


SN54LS687 . . . FK PACKAGE
(TOP VIEW)

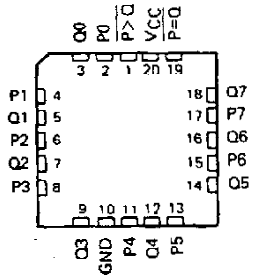


NC – No internal connection

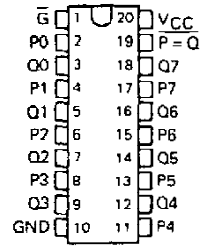
SN54LS682, SN54LS684, SN54LS685 . . . J PACKAGE
SN74LS682, SN74LS684, SN74LS685 . . . DW OR N PACKAGE
(TOP VIEW)



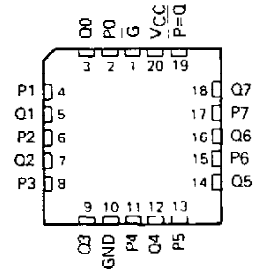
SN54LS682, SN54LS684, SN54LS685 . . . FK PACKAGE
(TOP VIEW)



SN54LS688 . . . J PACKAGE
SN74LS688 . . . DW OR N PACKAGE
(TOP VIEW)



SN54LS688 . . . FK PACKAGE
(TOP VIEW)



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SN54LS682, SN54LS684, SN54LS685, SN54LS687, SN54LS688
SN74LS682, SN74LS684 THRU SN74LS688
8-BIT MAGNITUDE/IDENTITY COMPARATORS

description

These magnitude comparators perform comparisons of two eight-bit binary or BCD words. All types provide $\overline{P = Q}$ outputs and all except 'LS688 provide $\overline{P > Q}$ outputs as well. The 'LS682, 'LS684, 'LS686, and 'LS688 have totem-pole outputs, while the 'LS685 and 'LS687 have open-collector outputs. The 'LS682 features 20-kΩ pullup termination resistors on the Q inputs for analog or switch data.

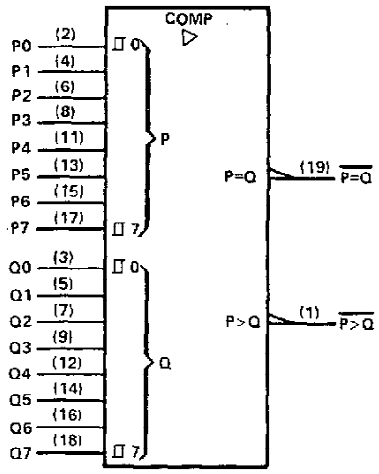
FUNCTION TABLE

INPUTS			OUTPUTS	
DATA	ENABLES		$\overline{P=Q}$	$\overline{P>Q}$
P, Q	$\overline{G}$, $\overline{G1}$	$\overline{G2}$		
P = Q	L	X	L	H
P > Q	X	L	H	L
P < Q	X	X	H	H
P = Q	H	X	H	H
P > Q	X	H	H	H
X	H	H	H	H

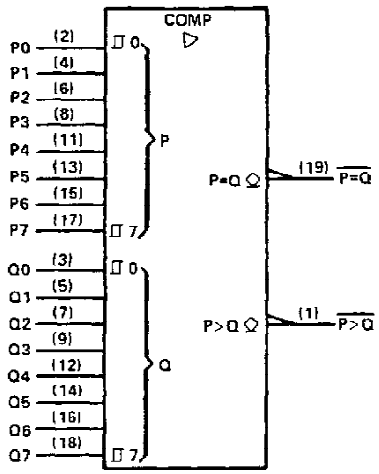
NOTES: 1. The last three lines of the function table applies only to the devices having enable inputs, i.e., 'LS686 thru 'LS688.
2. The $\overline{P<Q}$ function can be generated by applying the $\overline{P=Q}$ and $\overline{P>Q}$ outputs to a 2-input NAND gate.
3. For 'LS686 and 'LS687, $\overline{G}1$ enables $\overline{P=Q}$ and $\overline{G}2$ enables $\overline{P>Q}$.

logic symbols†

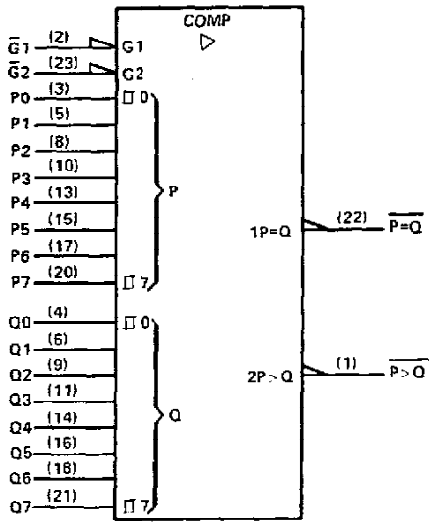
'LS682, 'LS684



'LS685



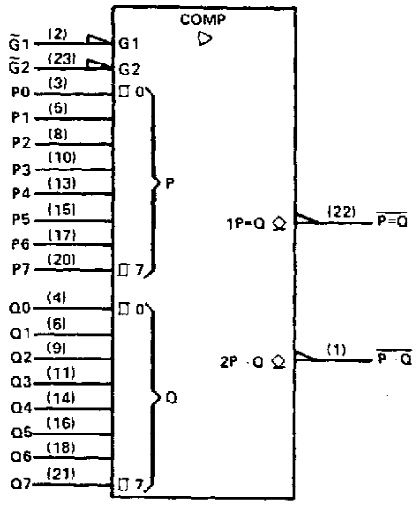
'LS686



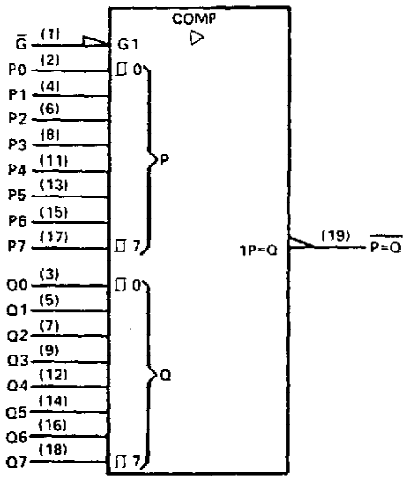
†These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for DW, J, JT, N, and NT packages.

logic symbols† (continued)

'LS687

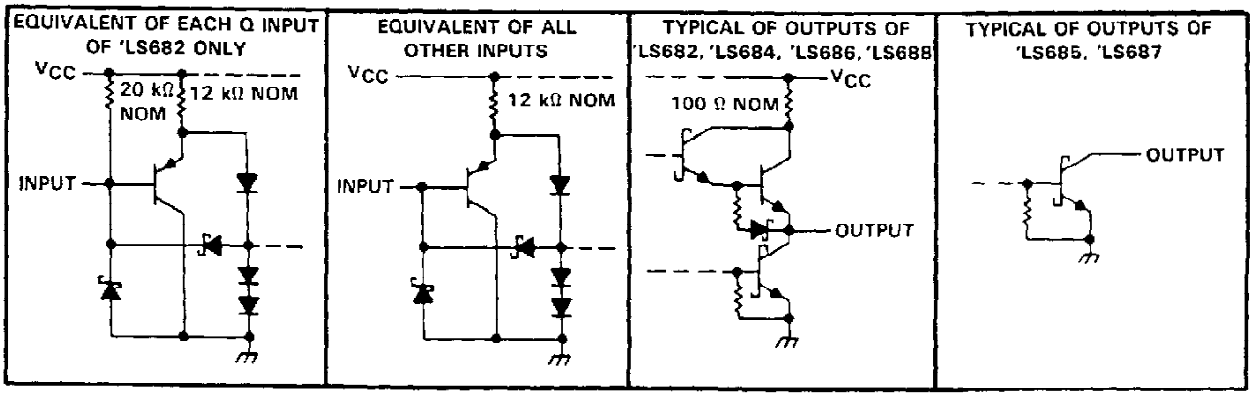


'LS688

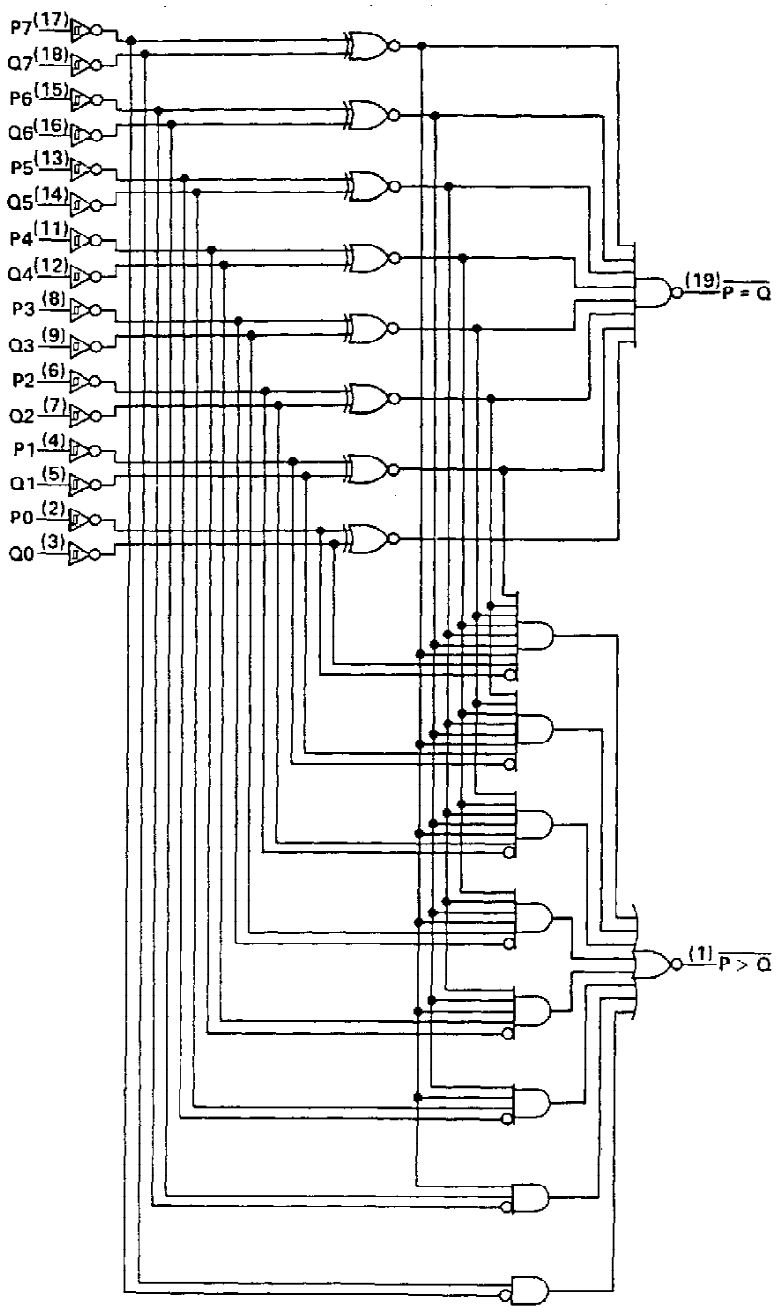


†These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for DW, J, JT, N, and NT packages.

schematics of inputs and outputs

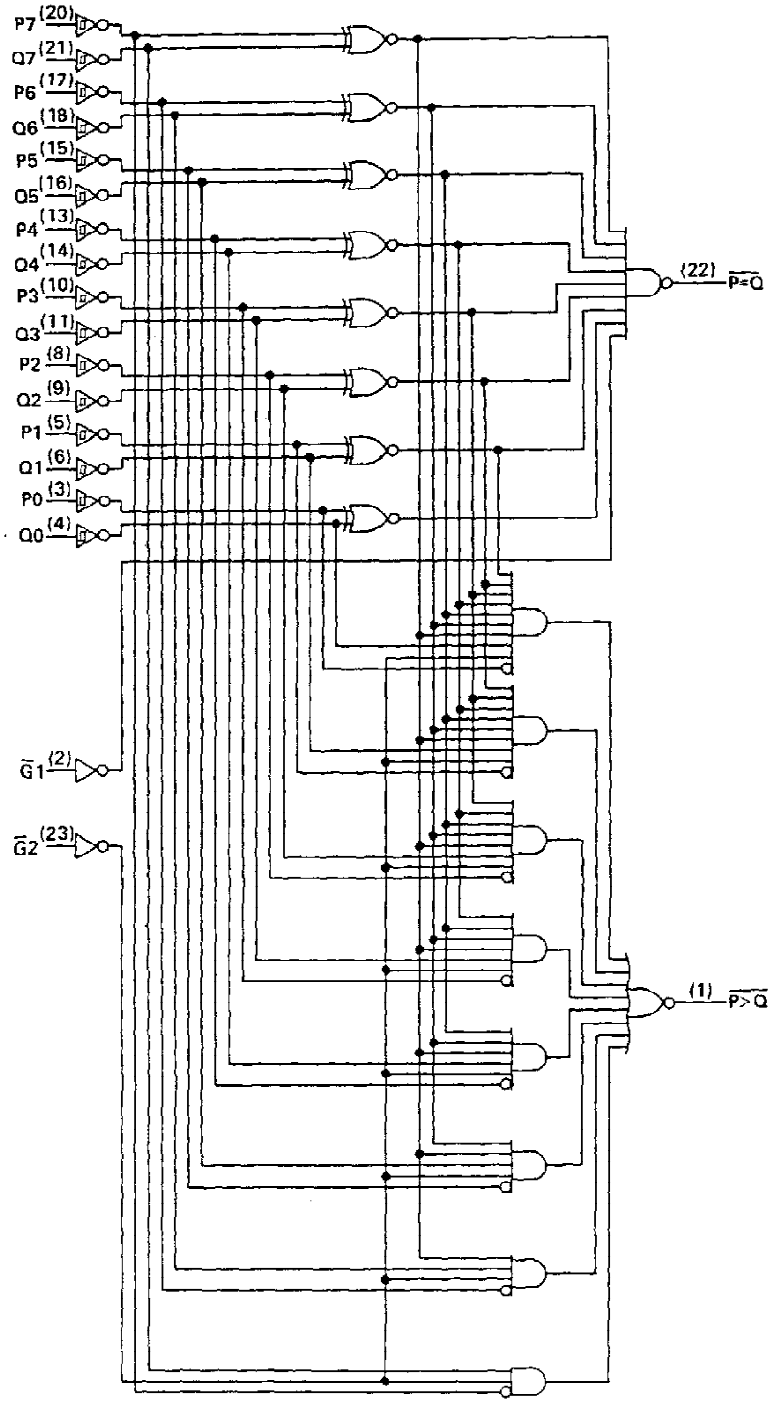


'LS682, 'LS684, 'LS685 logic diagram (positive logic)



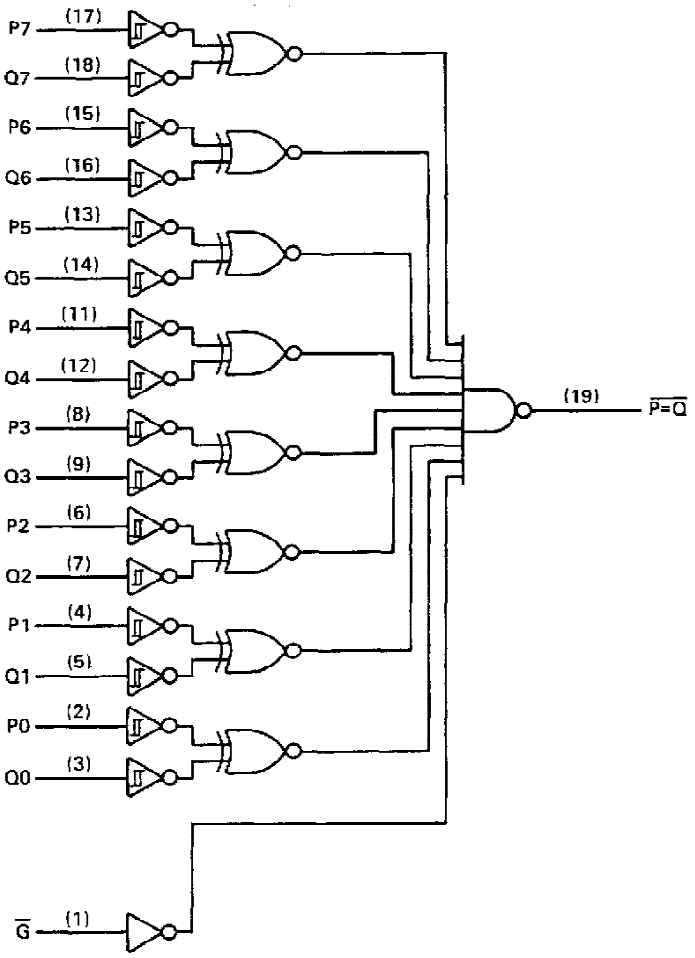
Pin numbers shown are for DW, J, and N packages.

'LS686, 'LS687 logic diagram (positive logic)



Pin numbers shown are for DW, JT, and NT packages.

'LS688 logic diagram (positive logic)



Pin numbers shown are for DW, J, and N packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1) . . . . . 7 V
Input voltage: Q inputs of 'LS682 . . . . . 5.5 V
All other inputs . . . . . 7 V
Off-state output voltage: 'LS685, 'LS687 . . . . . 7 V
Operating free-air temperature range:
SN54LS682, SN54LS684, SN54LS685, SN54LS687, SN54LS688 . . . . . −55°C to 125°C
SN74LS682, SN74LS684 thru SN74LS688 . . . . . 0°C to 70°C
Storage temperature range . . . . . −65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

	SN54LS'			SN74LS'			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, V_{CC}	4.5	5	5.5	4.85	5	5.25	V
High-level output current, I_{OH}			−400			−400	μA
Low-level output current, I_{OL}			12			24	mA
Operating free-air temperature, T_A	−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER			TEST CONDITIONS†		SN54LS'			SN74LS'			UNIT
					MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V_{IH}	High-level input voltage				2			2			V
V_{IL}	Low-level input voltage						0.7			0.8	V
$V_{T+}-V_{T-}$	Hysteresis	P or Q inputs	V_{CC} = MIN			0.4			0.4		V
V_{IK}	Input clamp voltage		V_{CC} = MIN,	I_I = −18 mA			−1.5			−1.5	V
V_{OH}	High-level output voltage		V_{CC} = MIN, V_{IL} = V_{IL}max,	V_{IH} = 2 V, I_{OH} = −400 μA	2.5			2.7			V
V_{OL}	Low-level output voltage		V_{CC} = MIN, V_{IH} = 2 V, V_{IL} = V_{IL}max,	I_{OL} = 12 mA		0.25	0.4		0.25	0.4	V
				I_{OL} = 24 mA					0.35	0.5	
I_I	Input current at maximum input voltage	Q inputs, 'LS682	V_{CC} = MAX,	V_I = 5.5 V			0.1			0.1	mA
		All other inputs	V_{CC} = MAX,	V_I = 7 V							
I_{IH}	High-level input current		V_{CC} = MAX,	V_I = 2.7 V			20			20	μA
I_{IL}	Low-level input current	Q inputs, 'LS682	V_{CC} = MAX,	V_I = 0.4 V			−0.4			−0.4	mA
		All other inputs					−0.2			−0.2	
I_{OS}§	Short-circuit output current		V_{CC} = MAX,	V_O = 0	−20		−100	−20		−100	mA
I_{CC}	Supply current	'LS682	V_{CC} = MAX,	See Note 1		42	70		42	70	mA
		'LS684				40	65		40	65	
		'LS686				44	75		44	75	
		'LS688				40	65		40	65	

† For conditions shown as MIN or MAX, use the appropriate values specified under recommended operating conditions.
‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.
§ Not more than one output should be shorted at a time, and duration of the short-circuit should not exceed one second.
NOTE 1: I_{CC} is measured with any $\overline{G}$ inputs grounded, all other inputs at 4.5 V, and all outputs open.

switching characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER†	FROM (INPUTS)	TO (OUTPUT)	TEST CONDITIONS	'LS682			'LS684			'LS686			'LS688			UNIT
				MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
t_{PLH}	P	$\overline{P=Q}$	R_L = 667 Ω, C_L = 45 pF, All other inputs low, See Note 2		13	25		15	25		13	25		12	18	ns
t_{PHL}					15	25		17	25		20	30		17	23	
t_{PLH}	Q	$\overline{P=Q}$			14	25		16	25		13	25		12	18	ns
t_{PHL}					15	25		15	25		21	30		17	23	
t_{PLH}	$\overline{G}$, $\overline{G}1$	$\overline{P=Q}$									11	20		12	18	ns
t_{PHL}											19	30		13	20	
t_{PLH}	P	$\overline{P>Q}$			20	30		22	30		19	30				ns
t_{PHL}					15	30		17	30		15	30				
t_{PLH}	Q	$\overline{P>Q}$			21	30		24	30		18	30				ns
t_{PHL}					19	30		20	30		19	30				
t_{PLH}	$\overline{G}2$	$\overline{P>Q}$									21	30				ns
t_{PHL}											16	25				

†t_{PLH} = propagation delay time, low-to-high-level outputs; t_{PHL} = propagation delay time, high-to-low-level output.
NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

recommended operating conditions

	SN54LS'			SN74LS'			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, V_{CC}	4.5	5	5.5	4.85	5	5.25	V
High-level output current, V_{OH}			5.5			5.5	V
Low-level output current, I_{OL}			12			24	mA
Operating free-air temperature, T_A	−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER			TEST CONDITIONS†		SN54LS'			SN74LS'			UNIT
					MIN	TYP	MAX	MIN	TYP	MAX	
V_{IH}	High-level input voltage				2			2			V
V_{IL}	Low-level input voltage						0.7			0.8	V
$V_{T+} - V_{T-}$	Hysteresis	P or Q inputs	V_{CC} = MIN			0.4			0.4		V
V_{IK}	Input clamp voltage		V_{CC} = MIN,	I_I = −18 mA			−1.5			−1.5	V
I_{OH}	High-level output voltage		V_{CC} = MIN, V_{IL} = V_{IL}max,	V_{IH} = 2 V, V_{OH} = 5.5 V			250			100	μA
V_{OL}	Low-level output voltage		V_{CC} = MIN, V_{IH} = 2 V, V_{IL} = V_{IL}max,	I_{OL} = 12 mA		0.25	0.4		0.25	0.4	V
				I_{OL} = 24 mA					0.35	0.5	
I_I			V_{CC} = MAX,	V_I = 7 V			0.1			0.1	mA
I_{IH}	High-level input current		V_{CC} = MAX,	V_I = 2.7 V			20			20	μA
I_{IL}	Low-level input current		V_{CC} = MAX,	V_I = 0.4 V			−0.2			−0.2	mA
I_{CC}	Supply current	'LS685	V_{CC} = MAX,	See Note 1		40	65		40	65	mA
		'LS687				44	75		44	75	

†For conditions shown as MIN or MAX, use the appropriate values specified under recommended operating conditions.
‡All typical values are at V_{CC} = 5 V, T_A = 25°C.
NOTE 1: I_{CC} is measure with any $\overline{G}$ inputs grounded, all other inputs at 4.5 V, and all outputs open.

switching characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	'LS685			'LS687			UNIT
				MIN	TYP	MAX	MIN	TYP	MAX	
t_{PLH}	P	$\overline{P=Q}$	R_L = 667 Ω, C_L = 45 pF, All other inputs low, See Note 2		30	45		24	35	ns
t_{PHL}					19	35		20	30	
t_{PLH}	Q	$\overline{P=Q}$			24	45		24	35	ns
t_{PHL}					23	35		20	30	
t_{PLH}	$\overline{G}$, $\overline{G}1$	$\overline{P=Q}$						21	35	ns
t_{PHL}								18	30	
t_{PLH}	P	$\overline{P>Q}$			32	45		24	35	ns
t_{PHL}					16	35		16	30	
t_{PLH}	Q	$\overline{P>Q}$			30	45		24	35	ns
t_{PHL}					20	35		16	30	
t_{PLH}	$\overline{G}2$	$\overline{P>Q}$						24	35	ns
t_{PHL}								15	30	

†t_{PLH} = propagation delay time, low-to-high-level outputs; t_{PHL} = propagation delay time, high-to-low-level output.
NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

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